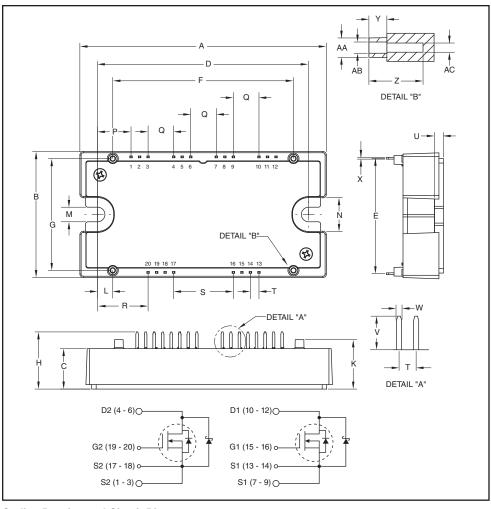


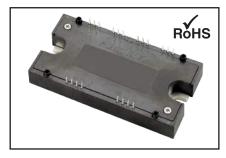
### Split Dual SiC **MOSFET Module** 100 Amperes/1200 Volts



### **Outline Drawing and Circuit Diagram**

Dimensions	Inches	Millimeters
А	4.32	109.8
В	2.21	56.1
С	0.71 18.0	
D	3.70±0.02	94.0±0.5
E	2.026	51.46
F	3.17	80.5
G	1.96	49.8
Н	1.00	25.5
K	0.87	22.0
L	0.266	6.75
М	0.26	6.5
N	0.59	15.0
Р	0.586	14.89

Dimensions	Inches	Millimeters
Q	0.449	11.40
R	0.885	22.49
S	1.047	26.6
Т	0.15	3.80
U	0.16	4.0
V	0.30	7.5
W	0.045	1.15
Χ	0.03	0.8
Υ	0.16	4.0
Z	0.47	12.1
AA	0.17 Dia.	4.3 Dia.
AB	0.10 Dia.	2.5 Dia.
AC	0.08 Dia.	2.1 Dia.



### **Description:**

Powerex Silicon Carbide MOSFET Modules are designed for use in high frequency applications. Each module consists of two MOSFET Silicon Carbide Transistors with each transistor having a reverse connected fast recovery free-wheel silicon carbide Schottky diode. All components and interconnects are isolated from the heat sinking baseplate, offering simplified system assembly and thermal management.

#### Features:

- ☐ Junction Temperature: 175°C ☐ Silicon Carbide Chips
- ☐ Low Internal Inductance
- ☐ Industry Leading RDS(on)
- ☐ High Speed Switching
- ☐ Low Switching Losses
- □ Low Capacitance ☐ Low Drive Requirement
- ☐ Fast 100A Free Wheeling Schottky Diode
- ☐ High Power Density
- ☐ Isolated Baseplate □ Aluminum Nitride Isolation
- □ 2 Individual Switches
- per Module
- Copper Baseplate ☐ RoHS Compliant

### **Applications:**

- □ Energy Saving Power Systems such as:
  - Fans; Pumps; Consumer **Appliances**
- ☐ High Frequency Type Power Systems such as:
  - UPS; High Speed Motor Drives; Induction Heating; Welder; Robotics
- ☐ High Temperature Power Systems such as:

Power Electronics in Electric Vehicle and Aviation Systems



QJD1210010 Split Dual SiC MOSFET Module 100 Amperes/1200 Volts

### Absolute Maximum Ratings, $T_j = 25$ °C unless otherwise specified

Ratings	Symbol	QJD1210010	Units	
Drain-Source Voltage (G-S Short)	V <sub>DSS</sub>	1200	Volts	
Gate-Source Voltage	V <sub>GSS</sub>	-5 / +25	Volts	
Drain Current (Continuous) at T <sub>C</sub> = 150°C	ID	100	Amperes	
Drain Current (Pulsed)*	I <sub>D(pulse)</sub>	250	Amperes	
Maximum Power Dissipation (T <sub>C</sub> = 25°C, T <sub>j</sub> < 175°C)	P <sub>D</sub>	1080	Watts	
Junction Temperature	Тј	-40 to 175	°C	
Storage Temperature	T <sub>stg</sub>	-40 to 150	°C	
Mounting Torque, M6 Mounting Screws	_	40	in-lb	
Module Weight (Typical)	_	270	Grams	
V Isolation Voltage	V <sub>RMS</sub>	3000	Volts	

 $<sup>^{\</sup>star}$  Pulse width and repetition rate should be such that device junction temperature (Tj) does not exceed Tj(max) rating.



QJD1210010 Split Dual SiC MOSFET Module 100 Amperes/1200 Volts

### MOSFET Characteristics, $T_j$ = 25 °C unless otherwise specified

Characteristics	Symbol	Test Conditions	Min.	Тур.	Max.	Units
Drain-Source Breakdown Voltage	V <sub>(BR)DSS</sub>	$I_D = 50\mu A, V_{GS} = 0$	1200	_		Volts
Zero Gate Voltage Drain Current**	IDSS	V <sub>GS</sub> = 0, V <sub>DS</sub> = 1200V	_	0.35	2.6	mA
Zero Gate Voltage Drain Current**	IDSS	V <sub>GS</sub> = 0, V <sub>DS</sub> = 1200V, T <sub>j</sub> = 175°C	_	0.40	4.0	mA
Gate Leakage Current	IGSS	V <sub>DS</sub> = 0, V <sub>GS</sub> = 20V	_	_	1.5	μΑ
Gate Threshold Voltage	V <sub>GS(th)</sub>	$V_{DS} = V_{GS}$ , $I_D = 10$ mA	1.5	2.5	5.0	Volts
		$V_{DS} = V_{GS}$ , $I_D = 10$ mA, $T_j = 175$ °C	1.0	1.7	5.0	Volts
Drain-Source On Resistance	R <sub>DS(on)</sub>	I <sub>D</sub> = 100A, V <sub>GS</sub> = 20V	_	15	25	mΩ
		$I_D = 100A$ , $V_{GS} = 20V$ , $T_j = 175$ °C	_	20	32	mΩ
Gate to Source Charge	Q <sub>gs</sub>	V <sub>DD</sub> = 800V, I <sub>D</sub> = 100A	_	140	_	nC
Gate to Drain Charge	Q <sub>gd</sub>	V <sub>DD</sub> = 800V, I <sub>D</sub> = 100A	_	220	_	nC
Total Gate Charge	QG	$V_{CC} = 800V$ , $I_{C} = 100A$ , $V_{GS} = -5/20V$	_	500	_	nC
Body Diode Forward Voltage	V <sub>SD</sub>	IF = 50A, VGS = -5V	_	4.0	_	Volts
Input Capacitance	C <sub>iss</sub>		_	10.2	_	nF
Output Capacitance	C <sub>oss</sub>	V <sub>GS</sub> = 0, V <sub>DS</sub> = 800V, f = 1MHz	_	1.0	_	nF
Reverse Transfer Capacitance	C <sub>rss</sub>		_	0.1	_	nF
Turn-on Delay Time	<sup>t</sup> d(on)	V <sub>DD</sub> = 800V, I <sub>D</sub> = 100A,	_	17.2	_	ns
Rise Time	t <sub>r</sub>	V <sub>GS</sub> = -2/20V,	_	13.6	_	ns
Turn-off Delay Time	t <sub>d</sub> (off)	$R_{G} = 6.8\Omega$	_	62	_	ns
Fall Time	t <sub>f</sub>	Inductive Load	_	35.6	_	ns

<sup>\*\*</sup>Total module leakage includes MOSFET leakage plus reverse Schottky diode leakage.



QJD1210010 Split Dual SiC MOSFET Module 100 Amperes/1200 Volts

### Reverse Schottky Diode Characteristics, $T_j$ = 25 °C unless otherwise specified

Characteristics	Symbol	Test Conditions	Min.	Тур.	Max.	Units
Diode Forward Voltage	VFM	$I_F = 100A, V_{GS} = -5V$	_	1.6	2.0	Volts
		$I_F = 100A$ , $V_{GS} = -5V$ , $T_j = 175$ °C	_	2.5	3.2	Volts
Diode Capacitive Charge	QC	V <sub>R</sub> = 1200V, I <sub>F</sub> = 100A, di/dt = 4000A/μs	_	550	_	nC

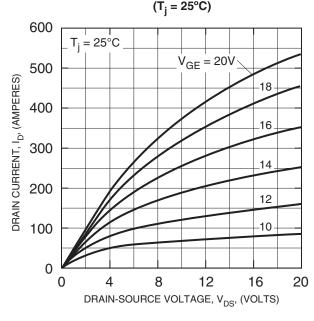
### Thermal and Mechanical Characteristics, $T_i$ = 25 °C unless otherwise specified

Characteristics	Symbol	Test Conditions	Min.	Typ.	Max.	Units
Thermal Resistance, Junction-to-Case	Rth(j-c)	MOSFET Part	_	_	0.138	°C/W
Thermal Resistance, Junction-to-Case	R <sub>th(j-c)</sub>	Diode Part	_	_	0.243	°C/W
Contact Thermal Resistance	R <sub>th(c-s)</sub>	Per 1/2 Module, Thermal Grease Applied	_	0.04	_	°C/W
Internal Inductance	Lint	MOSFET Part	_	10	_	nΗ

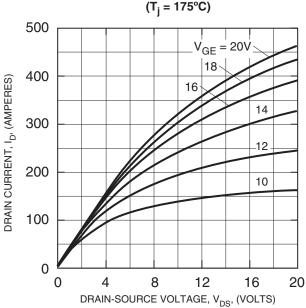


#### QJD1210010 Split Dual SiC MOSFET Module 100 Amperes/1200 Volts

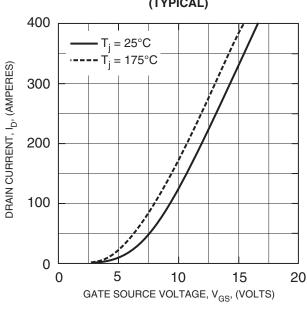
## TYPICAL OUTPUT CHARACTERISTICS



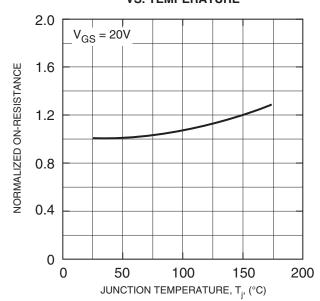
### TYPICAL OUTPUT CHARACTERISTICS (T. = 175°C)



### TRANSFER CHARACTERISTICS (TYPICAL)



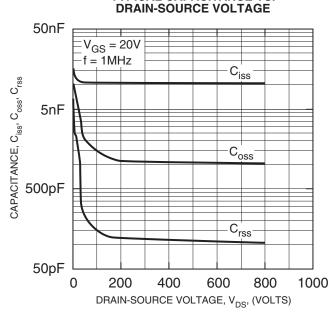
### NORMALIZED ON-RESISTANCE VS. TEMPERATURE



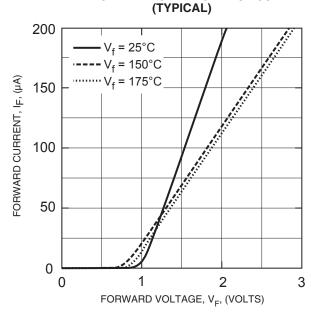


#### QJD1210010 Split Dual SiC MOSFET Module 100 Amperes/1200 Volts

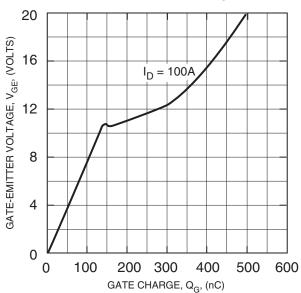
# TYPICAL CAPACITANCE VS.



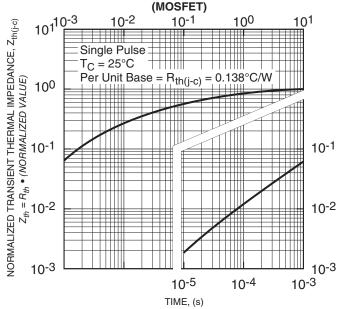
## FREE-WHEEL SCHOTTKY DIODE FORWARD CHARACTERISTICS



### GATE CHARGE VS. VGE



## TRANSIENT THERMAL IMPEDANCE CHARACTERISTICS





QJD1210010 Split Dual SiC MOSFET Module 100 Amperes/1200 Volts

